

Electronic Patent Application Fee Transmittal

Application Number:	10786807			
Filing Date:	25-Feb-2004			
Title of Invention:	Method for improving semiconductor wafer test accuracy			
First Named Inventor/Applicant Name:	Hui-Mei Chen			
Filer:	Dennis Alan Duchene/Lynne Craig			
Attorney Docket Number:	085027-0106			
Filed as Large Entity				
Utility under 35 USC 111(a) Filing Fees				
Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Basic Filing:				
Pages:				
Claims:				
Miscellaneous-Filing:				
Petition:				
Patent-Appeals-and-Interference:				
Post-Allowance-and-Post-Issuance:				
Extension-of-Time:				
Extension - 1 month with \$0 paid	1251	1	130	130

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Miscellaneous:				
Request for continued examination	1801	1	810	810
Total in USD (\$)				940